

The performance limiting factors as RF MOSFETs scale down

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The measured RF performance of 0.5, 0.25, and 0.18 μm MOSFETs gradually saturates as scaling down occurs, which can be explained by the derived analytical equation and simulation. The source-drain overlap capacitance, $C_{\text{sub gd}}$, and non-quasi-static effect are the main factors but scale much slower than $L_{\text{sub g}}$.

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